Poly(3,4-ethylenedioxythiophene):Poly(styrenesulfonate)(PEDOT:PSS)-MolybdenumOxideCompositeFilmsAsHoleConductor For Efficient Planar Perovskite Solar CellsYurong Jiang*, Chen Li, Hairui Liu, Ruiping Qin, Heng Ma*

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From the Figure S1, it can be seen that the MoOx nano-spots can be seen on the ITO substrate. Therefore, the deposited MoOx is not continuous film.



Figure S1 a)SEM image of MoOx aqueous solution coating on the ITO, b) obtained from forward bias to short circuit(FB-SC) and from short circuit to forward bias(SC-FB).







Figure S3 SEM images of PEDOT:PSS with different MoO_x doping concentration a) 0mg/ml, b) 1mg/ml, c) 1.5mg/ml.

MoO_x characteristics

In order to investigate the chemical composition of the MoO_x thin films using lowtemperature solution processing, X-ray photoelectron spectrum (XPS) of the Mo 3d core level of MoOx film is shown in Figure 2a. The Mo 3d peak is deconvoluted to obtain the contributions of Mo⁵⁺(232.0eV for Mo3d5/2) and Mo⁶⁺(232.7eV, 236.0eV). Mo^{6+} and Mo^{5+} are found to be the major species present in the MoO_x . In addition, Mo⁵⁺ species are found to be 18.7 atomic rations (%). Mo⁵⁺ species are contributed to metal-like electrical properties of MoOx, which are beneficial for the collection of photo-generated charge carriers owing to the more favorable band structure and are finally able to increase J_{sc}. To investigate the application of MoOx in the field of organic-inorganic hybrid solar cells, the ultraviolet photo-electron spectroscopy (UPS) measurements of a pristine PEDOT:PSS film and MoO_x coated on glass substrate are carried out and the results are shown in Figure S4b. The work function of MoO_x (5.12eV) is higher than the pristine PEDOT:PSS (4.99eV), which indicates the MoO_x as hole conductor would result in a better energy alignment between ITO and perovskite active layer.



Figure.S4 a) XPS profiles for the MoOx layer. b) Their corresponding UPS spectra. c) AFM morphology($5\mu m \times 5\mu m$) of the MoOx layer. d) Three-dimensional AFM surface topographical image of the MoO_x layer.

Figure S4c shows the surface topographical image of MoO_x aqueous solution coated on glass by atomic force microscopy (AFM). The surface roughness values of the root mean square (RMS) are1.71 nm for the whole scanned area (Figure 4Sc and d), the nano-scale spots form with heights ranging from 4 to 8.7 nm. This result indicates that the MoO_x is presented as the nanoparticles and is not the continuous film on glass, which is consistent with the SEM image in Supporting Information Figure S1. This is also the reason that the MoO_x could not completely replace for the PEDOT:PSS as the hole conductor in PSCs although the MoO_x has a higher work function than PEDOT:PSS. This is presumably caused by shorting associated with pinholes on the MoO_x layer. However, based on a consideration that the MoO_x could ensure the better growth of high quality perovskite films, and high work function which can provide sufficient charge dissociation and extraction, a perfect hole interfacial film for PSCs is expected by mixing PEDOT:PSS-MoO_x.